

Common Clause Capacitance Switching PC37.100.2 TF
IEEE/PES Switchgear ADSCOM Committee
11 October 2011 Nashville
MEETING MINUTES

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Introductions –

6 members were present for first section

Harry Hirz the chair for C37.66 attended the meeting

Patent Slides were reviewed

11 members were present for the second section.

We discussed the latest draft document all the way through. The following issues were discussed:

- Renumbering of the document. Currently it starts at 4.10, but this is left over from C37.09a. Will also look into reducing the depth of the numbering
- Bring relevant definitions in from IEEE 100.
- Harry Hirz requested projected schedule for standard.
- Clarity of back-to-back capacitor switching ratings. Need to clarify necessary testing and how to specify rating. Define I_{bb} and f_{bb} .
- Add tolerance to 100% (LC2, CC2, BC2) testing. Currently test is specified with lower limit, but no upper limit.
- Discussion of 10-40% testing. The WG concluded that the testing is satisfactory for rating the switch from 0-100% of rated capacitive switching current. Summary of this discussion will be added to introduction.
- Clarification of single phase vs. 3 phase test circuit.
- V in 'Test Voltage' section should be labeled correctly.
- Preconditioning needs to be rewritten to be less specific to C37.09. Needs to be written to include reclosers, etc. There also needs to be further consideration for reclosers and other non-high voltage circuit breaker type devices.
- Cable and Line charging tests from 1247 should be integrated into this standard.

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- The sections currently labeled 4.10.1 (Applicability) and 4.10.2 (General) should be moved into the overview section
- Pete Meyer will write/find definition for 'sealed-for-life'.
- Possible section needed for damping components (pre-insertion resistors, inductors, etc). How to appropriately test (setup of inrush current) and class these devices.
- Address clarity of section currently labeled as 4.10.11.1 (c). Possibly rewrite as flow chart.
- Check C37.083 (synthetic testing standard) to make sure it aligns with synthetic testing in new standard.

The next meeting should still be coordinated with the meeting of C37.66 so that individuals with interest in both standards can attend. Each committee would like a session to itself then a combined session to discuss testing. If possible it would be nice if our meetings did not conflict with C37.04 we lost too many participants to .04.